

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Stephen R. Quake et al.

Application No.:

Filed:

For: IMPROVED METHOD AND
SYSTEM FOR SCANNING
APERTURELESS FLUORESCENCE
MICROSCOPE

Examiner:

Art Unit:

INFORMATION DISCLOSURE
STATEMENT UNDER 37 CFR §1.97 and
§1.98

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

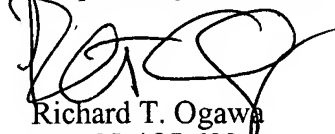
The references cited on attached form PTO/SB/08A and PTO/SB/08B are being called to the attention of the Examiner. Copies of the references are enclosed. It is respectfully requested that the cited references be expressly considered during the prosecution of this application, and the references be made of record therein and appear among the "references cited" on any patent to issue therefrom.

As provided for by 37 CFR 1.97(g) and (h), no inference should be made that the information and references cited are prior art merely because they are in this statement and no representation is being made that a search has been conducted or that this statement encompasses all the possible relevant information.

Applicant believes that no fee is required for submission of this statement. However, if a fee is required, the Commissioner is authorized to deduct such fee from the

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Respectfully submitted,



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First Named Inventor

Quake, Stephen R., et. al.

Art Unit

Examiner Name

Attorney Docket Number

020859-001310US

U.S. PATENT DOCUMENTS

Examiner	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number Kind Code ² (if known)			
	AA	US-6,002,471	12/14/99	Quake	
	AB	US-			
	AC	US-			
	AD	US-			
	AE	US-			
	AF	US-			
	AG	US-			
	AH	US-			
	AI	US-			
	AJ	US-			
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	† ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)				
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¹ Applicant's unique citation designation number (optional). ² Kind Codes of U.S. Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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**INFORMATION DISCLOSURE
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NON PATENT LITERATURE DOCUMENTS

Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	BC	H. GERSEN et al., "Near-field effects in single molecule emission", Journal of Microscopy, Vol. 202, Pt 2, May 2001, pp. 374-378	
	BD	H. GERSEN et al., "Influencing the Angular Emission of a Single Molecule", Physical Review Letters, Volume 85, Number 25, December 18, 2000, pp. 5312-5315	
	BE	J.M. GERTON et al., "Fluorescence Apertureless Near-field Optical Microscope for Biological Imaging", The 7th International Conference on Near-field Optics and Related Techniques, August 11-15, 2002, p. 71	
	BF	T.J. YANG et al., "An Apertureless Near-field Microscope for Fluorescence Imaging", Applied Physics Letters, Volume 76, Number 3, January 17, 2000, pp. 378-380	
	BG	GUILAUME A. LESSARD et al., "A Scanning Apertureless Fluorescence Microscope", Department of Applied Physics, California Institute of Technology, Pasadena, California, pp. 1-8	
	BH		
	BI		
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